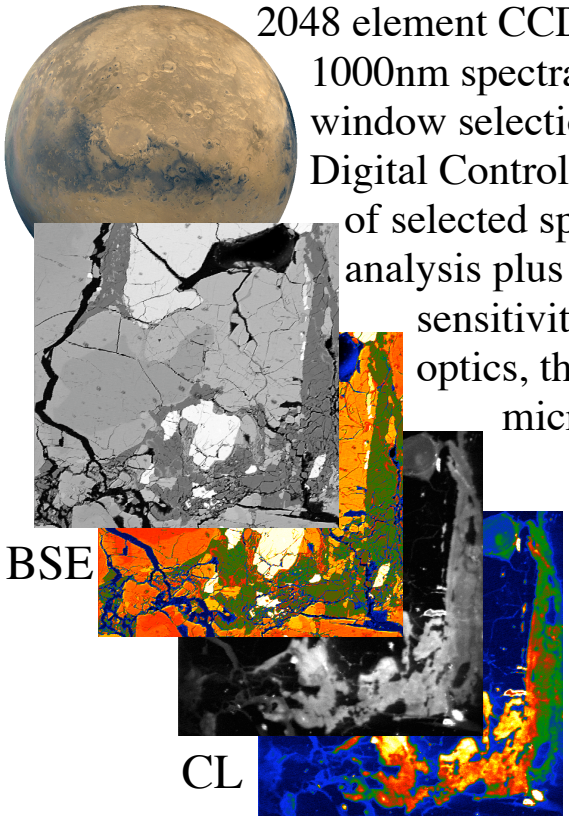
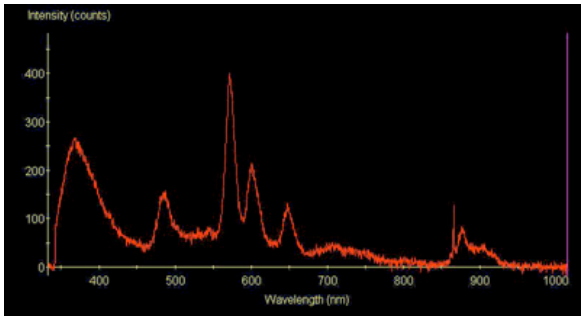
EOS CL IMAGING COMES TO LIGHT

Spectral Analysis plus high Resolution CL Imaging - From any Scanning Microscope

This system, updated for 2004, offers the most cost effective capability for analysis of Cathodoluminescence (CL) materials. A unique fiber optics interface allows accurate light alignment on fine grain samples for optimum collection efficiency. The detector geometry (as shown above) allows for simultaneous high resolution imaging in both secondary (SE) backscatter (BSD) and CL Modes. The spectrometer is a high sensitivity 2048 element CCD with selected grating optimized for 360-1000nm spectral coverage. Control software for a spectral window selection when used with the 4PI Revolution Digital Control System allows for compositional mapping of selected spectral elements. Offering full spectral analysis plus the ability to image via a super high sensitivity photomultiplier, interfaced to the fiber optics, the EOS CL System is a unique tool for the microanalyst.



Nakhla1401 -1 Mars Meteorite



CL Spectral Analysis

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